

STMICRO ELECTRONICSReport No.: CE/2004/C515020F, 207, TUN HUA SOUTH ROAD, SECTION 2,
TAIPEI 106, TAIWANDate: 2005/01/04Page: 1 of 2

The following merchandise was (were) submitted and identified by the client as :

<u>Type of Product</u>	:	IC
Style/Item No	:	TO-220AB
Sample Received	:	2004/12/28
Testing Date	:	2004/12/28 TO 2005/01/04

<u>Test Result</u>

PART NAME NO.1	:	SILVER COLORED METAL PIN (PLEASE REFER TO THE PHOTO
PART NAME NO.2	:	MIXED SILVER COLORED METAL/BLACK PLASTIC BODY (PLEASE
		REFER TO THE PHOTO ATTACHED)

				Result					
Test Item (s):	Unit	Method	MDL	No.1	No.2				
Chromium VI (Cr+6)	ppm	As per US EPA 7196A and US EPA 3060A.	2	N.D.	N.D.				
Cadmium (Cd)	ppm	ICP-AES after as per EN 1122, method B:2001 or other acid digestion.	2	N.D.	N.D.				
Mercury (Hg)	ppm	ICP-AES after as per US EPA 3052 or other acid digestion.	2	N.D.	N.D.				
Lead (Pb)	ppm	ICP-AES after as per US EPA 3050B or other acid digestion.		136.6	2841.9				

- NOTE : (1) N.D. = Not detected (<MDL)
 - (2) ppm = mg/kg
 - (3) MDL = Method Detection Limit

Operation Manager gned for and on behalf of

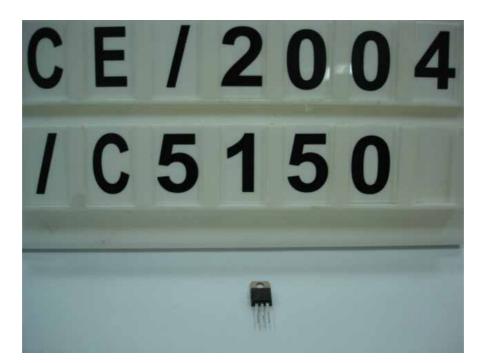
Signed for and on benan SGS TAIWAN LTD.

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